TOSHIBA FIELD EFFECT TRANSISTOR SILICON P CHANNEL MOS TYPE(U - MOS)

TPCF8104

Tentative

NOTE BOOK PC APPLICATIONS
PORTABLE EQUIPMENTS APPLICATIONS

UNIT:mm

Low Drain - Source ON Resistance: $R_{DS(ON)} = 26m$ (Typ.)

- High Forward Transfer Admittance: $|Y_{fs}| = S(Typ.)$
- Low Leakage Current : $I_{DSS} = -10 \mu A (Max.) (V_{DS} = -30 V)$
- Enhancement Mode : $V_{th} = -0.8 \sim -2.0 \text{ V} (V_{DS} = -10 \text{ V}, I_D = -1 \text{ mA})$

MAXIMUM RATINGS (Ta = 25)

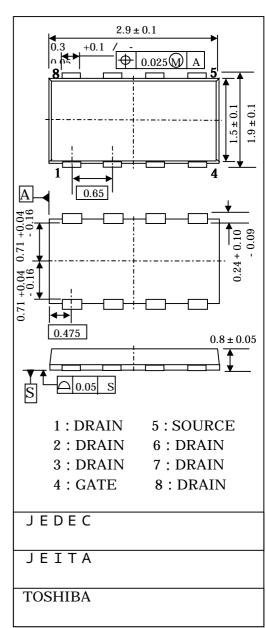
CHARACTER	SYMBOL	RATING	UNIT	
Drain - Source Volta	V _{DSS}	-30	V	
Drain - Gate Voltage	V _{DGR}	-30	V	
$(R_{GS} = 20 k)$				
Gate - Source Voltag	V _{GSS}	± 20	V	
Drain Current	DC (Note1)	ΙD	-6	Α
Drain Current	Pulse (Note1)	Ι _{DP}	-24	Α
Drain Power Dissi	pation (t=5s)	P _D	2.5	W
(Note2a)				
Drain Power Dissi	pation (t=5s)	P _D	0.7	W
(Note2b)				
Single Pulse Avalanch	E _{AS}	5.9	m J	
Avalanche Current	I _{AR}	3	Α	
Repetitive Avalanche		0.25	m J	
Channel Temperature	T _{c h}	150		
Storage Temperature	T _{stg}	- 55 ~ 150		

THERMAL CHARACTERISTICS

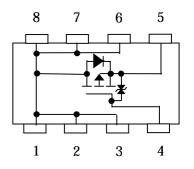
CHARACTERISTICS	SYMBOL	MAX.	UNIT	
Thermal Resistance, Channel to	R _{th(ch-a)}	50.0	/ W	
Ambient (t=5s) (Note2a)				
Thermal Resistance, Channel to	R _{th(ch-a)}	178.6	/ W	
Ambient (t=5s) (Note2b)	(

Note1, Note2, Note3, Note4, Note5 Please see next page.

THIS TRANSISTOR IS AN ELECTROSTATIC SENSITIVE DEVICE. PLEASE HANDLE WITH CAUTION.



Circuit Configuration



Tentative

ELECTRICAL CHARACTERISTICS (Ta = 25)

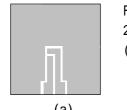
ELLOTRIONE OF	/////OTENTOTTOO (Ta	20)					
CHARA	CTERISTICS	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Gate Leakage	Current	I _{GSS}	$V_{GS} = \pm 16V$, $V_{DS} = 0V$	-	-	± 10	μΑ
Drain Cut-of	f Current	I _{DSS}	$V_{DS} = -30 V$, $V_{GS} = 0 V$	-	-	-10	μΑ
Drain-Source Breakdown		$V_{(BR)DSS}$	$I_D = -10 \text{m A}$, $V_{GS} = 0 \text{ V}$	-30	-	-	V
Voltage		$V_{(BR)DSX}$	$I_D = -10 \text{m A}$, $V_{GS} = 20 \text{ V}$	-15	-	-	V
Gate Thresho	old Voltage	V_{th}	$V_{DS} = -10V$, $I_D = -1mA$	-0.8	-	-2.0	V
Drain-Source	e ON Resistance	R _{DS(ON)}	$V_{GS} = -4.5V$, $I_D = 3A$	-	37	46	m
			$V_{GS} = -10V$, $I_D = -3A$	-	26	33	
Forward Tran	nsfer Admittance	Y _{f s}	$V_{DS} = -10V$, $I_D = -3A$	TBD	TBD	-	S
Input Capaci	Input Capacitance		$V_{DS} = -10 V , V_{GS} = 0 V$	-	TBD	-	
Reverse Tran	Reverse Transfer Capacitance		f = 1MHz	-	TBD	-	рF
Output Capac	itance	C _{rss}	1 - 1W1 F1 Z	-	TBD	-	
Switching Time	Rise Time	t r	0V	-	TBD	-	n s
	Turn-on Time	t _{o n}		-	TBD	-	
	Fall Time	t _f		-	TBD	-	
	Turn-off Time	t off		-	TBD	-	
Total Gate Charge (Gate-Source Plus Gate-Drain)		Q _g	V _{DD} -24V , V _{GS} = -10V	-	TBD	-	n C
Gate-Source Charge		Qgs	I _D = -6A	-	TBD	-	n C
Gate-Drain("Miller")Charge		Qgd		-	TBD	-	

SOURCE - DRAIN DIODE RATINGS AND CHARACTERISTICS (Ta = 25)

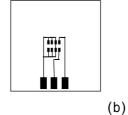
CHARACTERISTICS	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Pulse Drain Reverse Current	I _{DRP}	-	-	-	-24	Α
(Note1)						
Diode Forward Voltage	V _{DSF}	$I_{DR} = -6A$, $V_{GS} = 0V$	-	-	1.2	V

Note1 Please use devices on condition that the channel temperature is below 150 . Note2:

(a) Device mounted on glass-epoxy board (b) Device mounted on glass-epoxy board (b)



FR-4 $25.4 \times 25.4 \times 0.8$ (Unit in mm)



FR-4 $25.4 \times 25.4 \times 0.8$ (Unit in mm)

Note3: V_{DD} =-24V, Tch=25 (initial), L=0.5mH, R_G =25 , I_{AR} =-3.0A

Note4: Repetitive rating; Pulse Width Limited by Max. Channel Temperature.

TOSHIBA TPCF8104

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